

# Scattered Light Photoelastic Stress Meter

**Model: SLP-2000**



International Patent  
PCT: WO2018/056121

This machine is available to measure stress distribution of chemically tempered glass which is strengthened by ion-exchange from Li<sup>+</sup> to Na<sup>+</sup> using scattered light photoelasticity. In case of that the glass is strengthened by mixed liquid KNO<sub>3</sub> and NaNO<sub>3</sub>, K<sup>+</sup> layer should be measured by FSM-6000 and Na<sup>+</sup> layer should be measured by SLP-2000. These data can be combined by special software.

<Standard Deviation>

$\sigma$

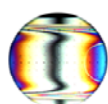
Model	Wavelength	CT_CV	DOL_Zero
SLP-1000	640nm	5.65MPa	2.16um
SLP-2000	520nm	1.51MPa	1.42um

- Actual data measuring the standard glass 20 times
- Required Refractive index and Photoelastic constant at the wavelength for measurement

## Specification

Range	: CS 0-2000 MPa, DOL 10-600 um
Resolution	: Stress 5 MPa Depth 5 um
Precision	: 50 um or deeper from surface Stress $\pm 10$ Mpa, Depth $\pm 5$ um (For standard glass)
Accuracy of standard glass	: CS $\pm 20$ Mpa, DOL_Zero $\pm 10$ um
Light source	: LD 520 $\pm 10$ nm, 18 mw, Class 3B
Application	: Chemically tempered glass, DIOX glass Thermally tempered glass
Object size	: Flat-1000R 10x10 mm or more
Prism refractive index	: 1.518 @518 nm
PC	: Preinstalled OS, special software
OS	: Windows 10/11 64 bit
Size (main body)	: W320xD280xH220 mm
Weight (main body)	: 11 kg

\* The combination requires optional FsmV/FsmX dongle.



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